



# TestForum On-line

## Join free On-line Info meetings and learn more about *Design for Testability*

Our recent On-line Webinar event on 'Test Automation', February 23, 2021 was a significant success. Three highly professional presentations including showcases delivered from Norway, Italy and the USA, and a participation including about 130 participants tell its own story.

Now *Nordic Test Forum* follows up with its next webinar, the focus being on '*Design for Testability*', *DfT*. Many test engineers have over time struggled with the challenge of testing electronic products that inherently resisted test due to poor support for testing. It needs not be like that. A well planned strategy for test of electronics products - already conceived during the phases of design, can help avoid situations, where exhaustive test resources are thrown into remedying problems that could have been handled through careful design for testability.

The webinar on "Design for Testability" focuses on outlining strategies on how to devise design of electronic products that lend themselves to efficient testing and hence improving product quality and reduces costs. Why throw resources into resolving problems that should never have emerged?

Join us on **Tuesday March 23, 2021 at 13:00 to 14:30 Central European time (Berlin, Paris and Copenhagen – and the webinar is for free!**

### Webinar on: 'Design for Testability'

#### Program

13:00 ***"Design for Testability – Best practices for integrating test into your design"***

Toni Ahrnt Bojsen, DSE Test Solutions, Denmark,

Many test engineers are struggling with long test times and poor test yield because a device under test is not designed well for test. In this session, we focus on design for testability of PCBAs (functional test), 'End of Line test' and why it is important to include test requirements within the embedded software of the device under test. The presentation is backed by many years of experience in developing production test systems. Practical guidelines, design hints and example layouts for PCBAs are provided.

13:30 ***"Design for Test (DfT) beyond Boundary Scan"***

Jan Heiber, Göpel electronic, Germany

Comprehensive testing requires special design preparations on today's assemblies. Because typically a single type of test cannot meet all quality requirements, one needs tools for cross-test analysis and reporting - multi-dimensional DfT analysis and test coverage reports. The presentation shows different embedded test options and covers test preparation, rounded up by example analyses and reports.

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